

**CPK**

**PURPOSE**

Compute the Process capability index ( $C_{pk}$ ) for a variable.

**DESCRIPTION**

The process capability index measures the performance (i.e., the “capability”) of an industrial process and is defined as follows:

$$C_{pk} = \text{MINIMUM}((USL - m), (m - LSL)) / (3s)$$

where USL and LSL are the upper and lower specification limits, m is the sample mean, and s is the sample standard deviation. The USL and LSL are user defined limits within which a product is considered acceptable (values outside these limits indicate that a product is defective). This is the asymmetric case for the  $C_p$  command. See the documentation for CP for a description of the  $C_p$  index.

**SYNTAX**

LET <par> = CPK <y> <SUBSET/EXCEPT/FOR qualification>

where <y> is a response variable;

<par> is a parameter where the computed  $C_{pk}$  index is stored;

and where the <SUBSET/EXCEPT/FOR qualification> is optional.

**EXAMPLES**

LET A = CPK Y1

LET A = CPK Y1 SUBSET TAG > 2

**NOTE 1**

Recall that Chebychev’s theorem states that at least 75% of a variables observations must fall within plus or minus 2 standard deviations of the mean and that at least 88% of them must fall within plus or minus 3 standard deviations. This is for any distribution. For a normal distribution, these numbers are 95.4% and 99.7% respectively.

**NOTE 2**

The upper and lower specification limits must be specified by the user as follows:

LET LSL = <value>

LET USL = < value>

**NOTE 3**

If the specification limits are symmetric about the mean, the CPK and the CP statistics are identical. The CPK statistic may be the better choice when this is not the case.

**DEFAULT**

None

**SYNONYMS**

None

**RELATED COMMANDS**

- CPK PLOT = Generate a  $C_{pk}$  versus subset plot.
- CONTROL CHART = Generate a control chart.
- CP = Compute the  $C_p$  index.
- PERCENT DEFECTIVE = Compute the percentage of defectives in a sample.
- EXPECTED LOSS = Compute the expected loss of a sample.

**REFERENCE**

“Guide to Quality Control,” Kaoru Ishikawa, Asian Productivity Organization, 1982.

**APPLICATIONS**

Quality Control

**IMPLEMENTATION DATE**

90/12

## PROGRAM

```
SKIP 25
READ GEAR.DAT DIAMETER
LET LSL = 0.99
LET USL = 1.01
LET A = CP DIAMETER
```

The computed  $C_p$  value is 0.40.